

10/569209

1AP20 Rec'd PCT/PTO 23 FEB 2006
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Takashi YAMADA et al.

Application No.: New U.S. National Stage of
PCT/JP2004/012302

Filed: February 23, 2006

Docket No.: 127154

For: WARPAGE ANGLE MEASUREMENT APPARATUS AND WARPAGE ANGLE
MEASUREMENT METHOD FOR OPTICAL RECORDING MEDIUM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of one or more non-English language reference is discussed in the present specification. See Reference 1.
- 3. One or more reference cited herein was cited in the International Search Report. An English language version of the International Search Report is attached for the Examiner's information. See References 2-13.
- 4. An English language Abstract of one or more non-English language reference is attached hereto. See References 1-12.

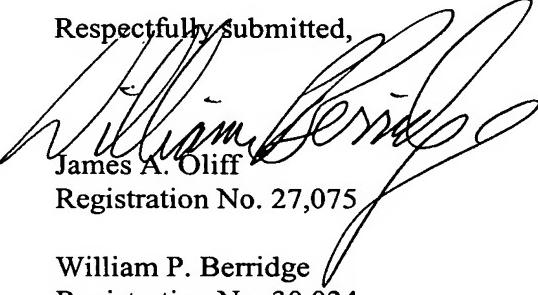
10/56920

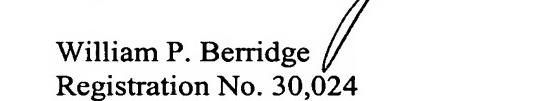
New U.S. National Stage of PCT/JP2004/012302

WP20 Rec'd PCT/PTO 23 FEB 2006

5. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([<http://www.jpo.go.jp>]), and is attached, but has not been reviewed for accuracy. See References 1-9 & 11.

Respectfully submitted,


James A. Oliff
Registration No. 27,075


William P. Berridge
Registration No. 30,024

JAO:WPB/crh

Date: February 23, 2006

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

**DEPOSIT ACCOUNT USE
AUTHORIZATION**
Please grant any extension
necessary for entry;
Charge any fee due to our
Deposit Account No. 15-0461

Form PTO-1449 (REV. 1/06)			US Dept. of Commerce PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)		ATTY DOCKET NO. 127154	10/569209 APPLICATION NO. New U.S. National Stage of PCT/JP2004/012302	
					APPLICANTS Takashi YAMADA et al.		
					FILING DATE February 23, 2006		
U.S. PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Name			
FOREIGN PATENT DOCUMENTS							
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation	
	1	JP A 2003-085836	03/20/2003	JAPAN	X	X	
	2	JP A 2003-091883	03/28/2003	JAPAN	X	X	
	3	JP A 2003-059097	02/28/2003	JAPAN	X	X	
	4	JP A 2003-132596	05/09/2003	JAPAN	X	X	
	5	JP A 08-233543	09/13/1996	JAPAN	X	X	
	6	JP A 2001-257461	09/21/2001	JAPAN	X	X	
	7	JP A 2001-041718	02/16/2001	JAPAN	X	X	
	8	JP A 2003-132591	05/09/2003	JAPAN	X	X	
	9	JP A 10-078310	03/24/1998	JAPAN	X	X	
	10	JP A 64-1904	01/06/1989	JAPAN	X		
	11	JP A 2002-313050	10/25/2002	JAPAN	X	X	
	12	JP A 04-276354	10/01/1992	JAPAN	X		
	13	JP U 05-90656	12/10/1993	JAPAN			
OTHER DOCUMENTS							
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)					
EXAMINER						DATE CONSIDERED	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							